

Notic of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	10/089,488	ARNONE ET AL.	
Examiner John D. Lee	<i>John D. Lee</i>	Art Unit 2874	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-4,943,145	07-1990	Miyata, Seizo	359/244
B	US-5,379,311	01-1995	McFarlane et al.	372/41
C	US-			
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J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages
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